

December 2010 UniFET-II

FDD5N60NZ N-Channel MOSFET 600V, 4.0A, 2Ω

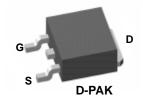
Features

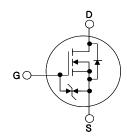
- $R_{DS(on)} = 1.65\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 2.0A$
- Low Gate Charge (Typ. 10nC)
- Low C_{rss} (Typ. 5pF)
- · Fast Switching
- 100% Avalanche Tested
- Improved dv/dt Capability
- · ESD Improved Capability
- RoHS Compliant

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

| Symbol | | Parameter | | FDD5N60NZ | Units |
|-----------------------------------|--|--------------------------------------|-------------------|-------------|-------|
| V _{DSS} | Drain to Source Voltage | | | 600 | V |
| V_{GSS} | Gate to Source Voltage | | | ±25 | V |
| | Drain Current | -Continuous (T _C = 25°C) | | 4.0 | А |
| ID | Drain Current | -Continuous (T _C = 100°C) | | 2.4 | A |
| I _{DM} | Drain Current | - Pulsed | - Pulsed (Note 1) | | |
| E _{AS} | Single Pulsed Avalanche En | ergy | (Note 2) | 216 | mJ |
| I _{AR} | Avalanche Current | | (Note 1) | 4.0 | А |
| E _{AR} | Repetitive Avalanche Energy | / | (Note 1) | 8.3 | mJ |
| dv/dt | Peak Diode Recovery dv/dt | | (Note 3) | 10 | V/ns |
| D | Dower Dissination | (T _C = 25°C) | | 83 | W |
| P_{D} | Power Dissipation | - Derate above 25°C | | 0.7 | W/°C |
| T _J , T _{STG} | Operating and Storage Temp | perature Range | | -55 to +150 | °C |
| TL | Maximum Lead Temperature 1/8" from Case for 5 Second | • • | | 300 | °C |

Thermal Characteristics

| Symbol | Parameter | Parameter FDD5N60NZ | |
|-----------------|--|---------------------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | 1.5 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient 90 | | C/VV |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-----------|---------|-----------|------------|----------|
| FDD5N60NZ | FDD5N60NZ | D-PAK | 380mm | 16mm | 2500 |

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Units |
|--------------------------------------|--|--|------|------|------|-------|
| Off Charac | cteristics | | | | | |
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = 250\mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$ | 600 | - | - | V |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | I _D = 250μA, Referenced to 25°C | - | 0.6 | - | V/°C |
| 1 | Zero Gate Voltage Drain Current | $V_{DS} = 600V, V_{GS} = 0V$ | - | - | 50 | |
| IDSS | Zero Gate voltage Drain Current | $V_{DS} = 480V, T_{C} = 125^{\circ}C$ | - | - | 100 | μΑ |
| I _{GSS} | Gate to Body Leakage Current | $V_{GS} = \pm 25V, V_{DS} = 0V$ | - | - | ±10 | μΑ |

On Characteristics

| V _{GS(th)} | Gate Threshold Voltage | $V_{GS} = V_{DS}, I_{D} = 250 \mu A$ | 3.0 | - | 5.0 | V |
|---------------------|--------------------------------------|--------------------------------------|------|------|------|---|
| R _{DS(on)} | Static Drain to Source On Resistance | $V_{GS} = 10V, I_D = 2.0A$ | - | 1.65 | 2.00 | Ω |
| 9 _{FS} | Forward Transconductance | $V_{DS} = 20V, I_{D} = 2.0A$ (Note | 4) - | 5 | - | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | V 05V V 0V | - | 450 | 600 | pF |
|---------------------|-------------------------------|---|---|-----|-----|----|
| Coss | Output Capacitance | $V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz | - | 50 | 65 | pF |
| C _{rss} | Reverse Transfer Capacitance | 1 - 11/11/2 | - | 5 | 7.5 | pF |
| Q _{g(tot)} | Total Gate Charge at 10V | | - | 10 | 13 | nC |
| Q _{gs} | Gate to Source Gate Charge | $V_{DS} = 400V, I_{D} = 4.0A$ | - | 2.5 | - | nC |
| Q_{gd} | Gate to Drain "Miller" Charge | V _{GS} = 10V (Note 4, 5 | - | 4 | - | nC |

Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | | - | 15 | 40 | ns |
|---------------------|---------------------|--------------------------------|---|----|----|----|
| t _r | | $V_{DD} = 250V, I_{D} = 4.0A$ | - | 20 | 50 | ns |
| t _{d(off)} | Turn-Off Delay Time | $V_{GS} = 10V, R_G = 25\Omega$ | - | 35 | 80 | ns |
| t _f | Turn-Off Fall Time | (Note 4, 5) | - | 20 | 50 | ns |

Drain-Source Diode Characteristics

| IS | Maximum Continuous Drain to Source Diode Forward Current | | | - | - | 4.0 | Α |
|-----------------|--|--|----------|---|-----|-----|----|
| I _{SM} | Maximum Pulsed Drain to Source Diode Forward Current | | | - | - | 16 | Α |
| V_{SD} | Drain to Source Diode Forward Voltage | $V_{GS} = 0V, I_{SD} = 4.0A$ | | - | - | 1.4 | V |
| t _{rr} | Reverse Recovery Time | V _{GS} = 0V, I _{SD} = 4.0A | | - | 230 | - | ns |
| Q _{rr} | Reverse Recovery Charge | $dI_F/dt = 100A/\mu s$ | (Note 4) | - | 0.9 | - | μС |

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 27mH, I $_{AS}$ = 4.0A, V $_{DD}$ = 50V, R $_{G}$ = 25 $\!\Omega$, Starting T $_{J}$ = 25 $^{\circ}C$
- 3. I $_{SD} \leq$ 4.0A, di/dt \leq 200A/µs, V $_{DD} \leq$ BV $_{DSS},$ Starting T $_{J}$ = 25°C
- 4. Pulse Test: Pulse width $\leq 300 \mu s, \, \text{Dual Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

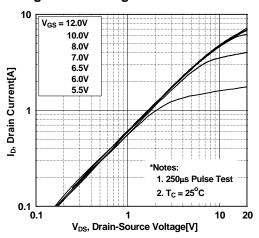


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

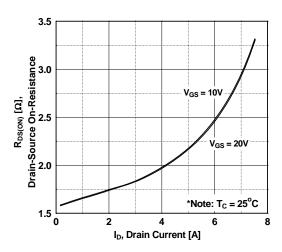


Figure 5. Capacitance Characteristics

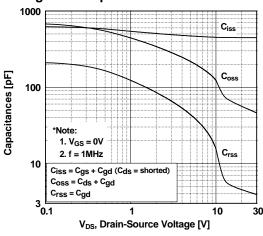


Figure 2. Transfer Characteristics

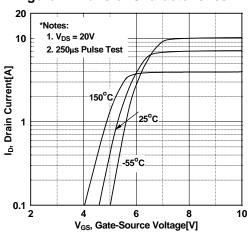


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

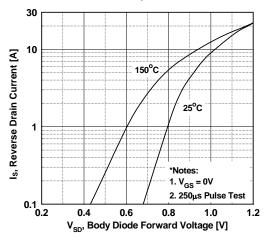
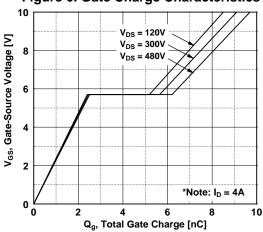


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

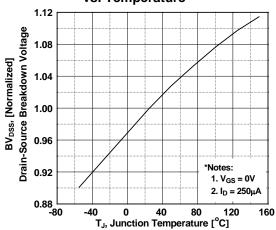


Figure 8. On-Resistance Variation vs. Temperature

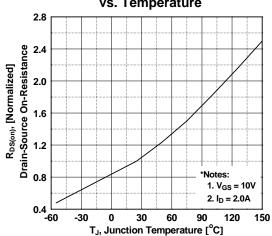


Figure 9. Maximum Safe Operating Area vs. Case Temperature

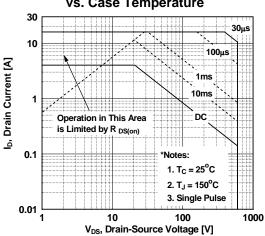


Figure 10. Maximum Drain Current

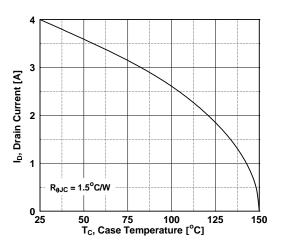
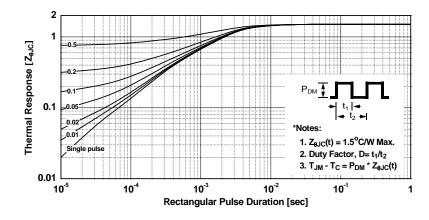
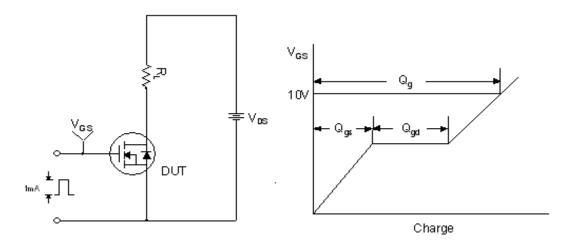


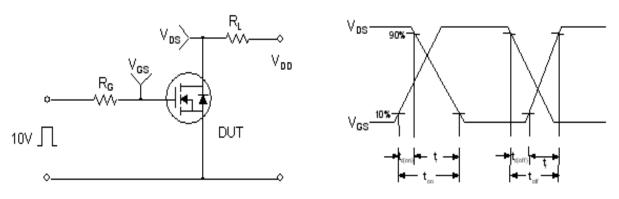
Figure 11. Transient Thermal Response Curve



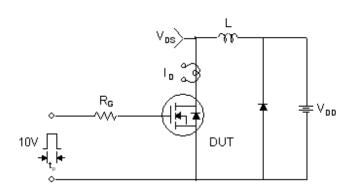
Gate Charge Test Circuit & Waveform

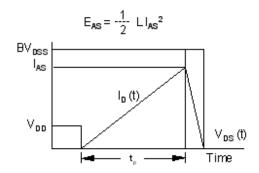


Resistive Switching Test Circuit & Waveforms

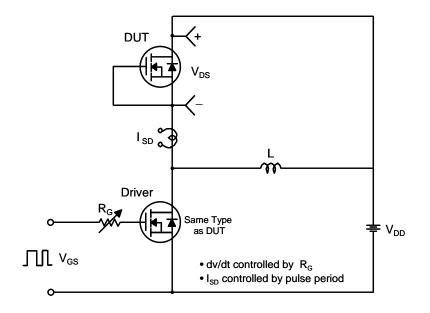


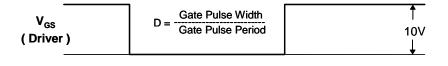
Unclamped Inductive Switching Test Circuit & Waveforms

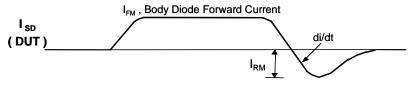




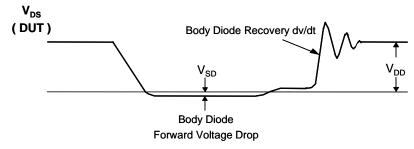
Peak Diode Recovery dv/dt Test Circuit & Waveforms





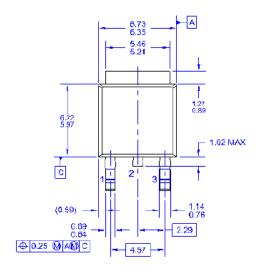


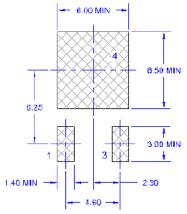
Body Diode Reverse Current



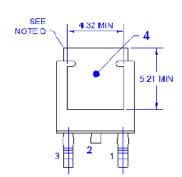
Mechanical Dimensions

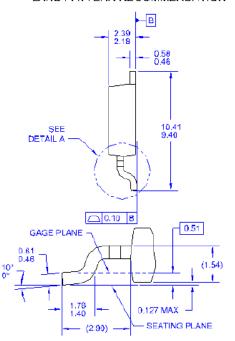
D-PAK





LAND PATTERN RECOMMENDATION





- NOTES: LINLESS OTHERWISE SPECIFIED

 A) THIS PACKAGE CONFORMS TO JEDEC, TO-252.
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 C) DINEMSIONING AND TOLENANCING PER
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 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED
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 E) PRESENCE OF TRIMMED CENTER LEAD
 IS OPTIONAL
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 MOLD FLASH AND THE BAR EXTRUSIONS.
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- TO220P1003X239-3N, H: DRAWING NUMBER AND REVISION: WKT-TO252A03REVB

Dimensions in Millimeters





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